## Particle size analyze

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#### Methods for determining particle size

- 1. Microscopy
- 2. Sieving
- 3. Laser light scattering techniques
- 4. Sedi mentation techniques
- **5.** electrical sensing zone method
- 6. Surface area measurement techniques



## 1. Microscopy

Optical microscopy (1-150µm) Electron microscopy (0.001µ)

- Being able to examine each particle alone has led to microscopy being considered as an absolute measurement of particle size.
- Can distinguish aggregates from single particles
- When coupled to image analysis computers each field can be examined, and a distribution obtained.
- Number distribution
- Most severe limitation of optical microscopy is the depth of focus being about 10µm at x100 and only 0.5µm at x1000.
- With small particles, diffraction effects increase causing spot at the edges - determination of particles < 3µm is less.</li>

## For sub Micron particles it is necessary to use either

- TEM (Transmission Electron Microscopy) or
- SEM (Scanning Electron Microscopy).
- TEM and SEM (0.001µm)

#### **Advantages**

- Relatively inexpensive
- Each particle individually examined detect aggregates, 2D shape, colour, melting point etc.
- Permanent record photograph
- Small sample sizes required

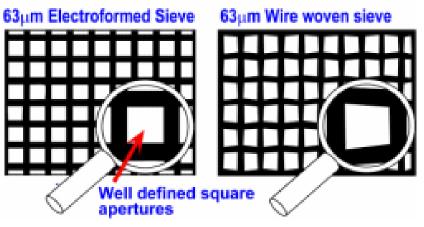
#### Disadvantages

- Time consuming high operator fatigue few particles examined
- Very low production
- No information on 3D shape



## 2. Sieving

- Sieve analysis is performed using a nest or stack of sieves where each lower sieve has a smaller aperture size than that of the sieve above it.
- Sieves can be referred to either by their aperture size or by their mesh size (or sieve number).
- The mesh size (is the number of wires per linear inch).
- Approx. size range : 5µm ~3mm
  - Standard woven wire sieves
  - Electroformed micromesh sieves at the lower end or range (< 20µm)</li>
  - ✓ Blow plate sieves at the upper range.



- Sieving may be performed wet or dry; by machine or by hand, for a fixed time or until powder passes through the sieve at a constant low rate
- Wet sieving
- Air-jet sieving
- Weight distribution





#### **Advantages**

- Easy to complete
- Wide size range
- Inexpensive

#### Disadvantages

- Wear/damage in use or cleaning
- Rough particles
- Rod-like particles : overestimate of under-size
- Work hard

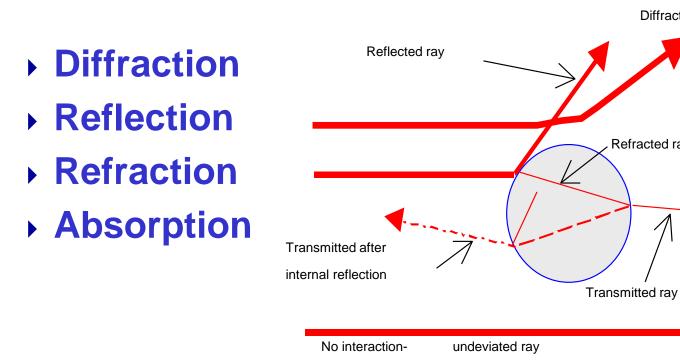
## **3.Laser Light Scattering**

- 1. Widely used fast technique that can be applied to various particulate systems
- 2. Easily automated in a variety of commercially available instruments
- 3. Requires knowledge of Refractive Index of the material (n)
- 4. Data presented as Equivalent Spherical Diameter

# Historically laser scattering (angles)

- was performed at small angles only, typically up to 14°, called
  - Fraunhofer diffraction
  - Forward light scattering
  - Low-angle laser light scattering (LALLS)
- Gave results down to 1 µm
- Now broadened to include wider angles with Mie Theory optical modeling
- Expanded range down to 0.1 µm

## **Types of Scattered Light**



Diffracted ray

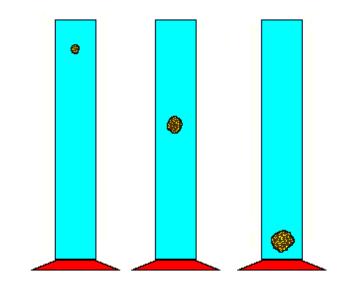
Refracted ray

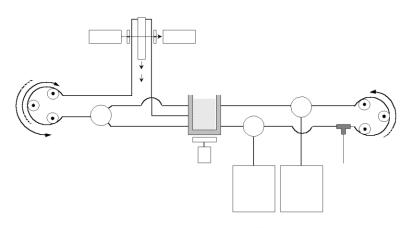
## 4.X-ray Se dimentation

- Based Upon a Classical Particle Sizing Method - Stokes' Law.
- Same Sizing Principle as Andreasen Pipette and Long-Arm Centrifuge.
- Direct Mass Concentration Detection.
- X-Ray Attenuation is Proportional to Mass in Beam.
- Material Density must be Known
- Widely used in the Ceramic Industry



- Mature, well understood and widely practiced technique.
- Now fully automated





## Stoke's equation

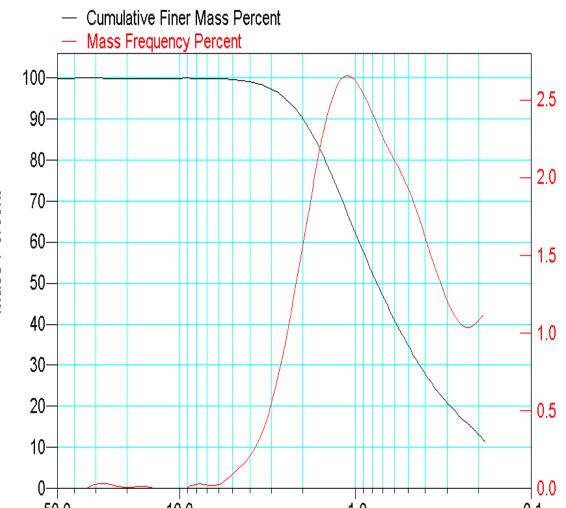
$$D = \sqrt{\frac{18*\eta*v}{(\rho - \rho_o)*g}}$$

- D = particle diameter
- $\eta =$  liquid viscosity
- v = sedimentation velocity
- $\rho = particle density$
- $\rho_o =$  liquid density
- g = acceleration due to gravity

- Accounts for Particle Mass Outside Analysis Range.
- Analyzes Higher Concentrated Slurries than Most Other Techniques.
- Provides Reliable Analyses of Wide Size Range: 300 µm to 0.1 µm.
- Requires Only Readily-Available Physical Constants as Parameters.

#### **Particle Size Distribution Analysis of Fine caco3 Sample.**

Cumulative Finer Mass Percent vs. Diameter

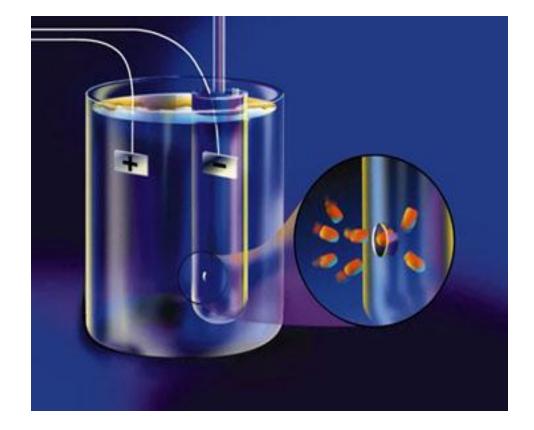


Mass Percent

## **5.Electrical Sensing Zone**

- Particle suspended in a conductive liquid, passing through a narrow orifice, increases resistance through the orifice
- Voltage must increase to keep constant current through orifice, same as Elzone 5380 and Multisizer 3
- Voltage change proportional to particle volume

## **Elzone Principle of Operation**





### **Advantages**

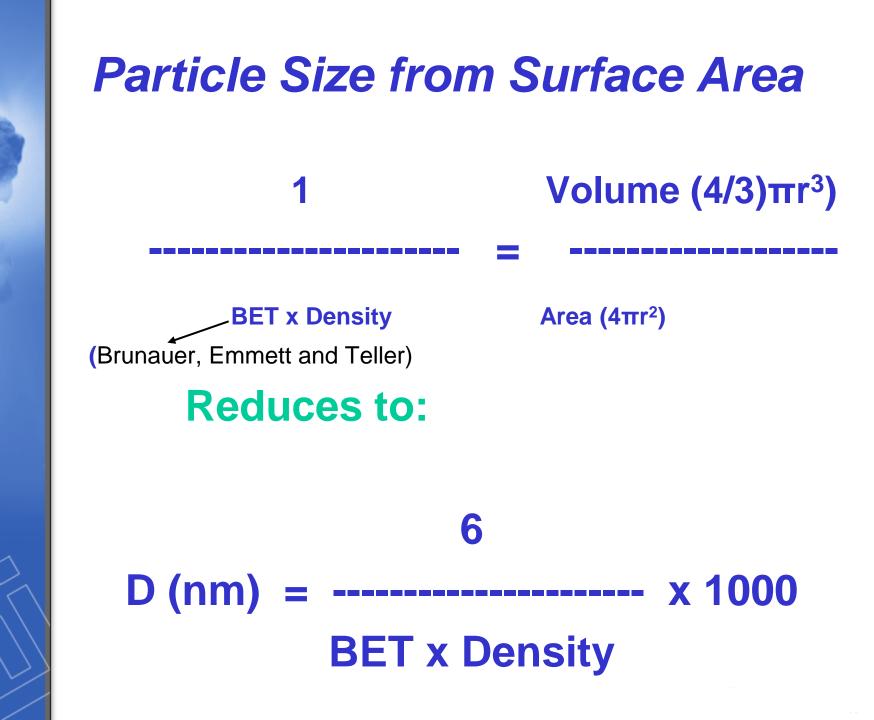
- 1. Counts and sizes organic and inorganic particles
- 2. Analyzes materials with mixed optical properties, densities and shapes
- 3. Higher resolution than other sizing methods
- 4. Lower quantity of sample needed for accurate, easy analysis
- 5. Compact size takes up little lab space
- 6. Automatic orifice blockage detection

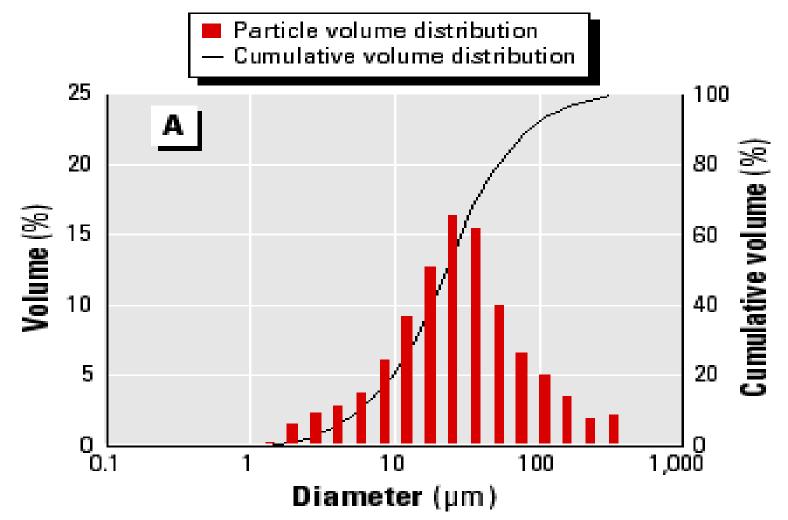
6. (Surface area measurement techniques)

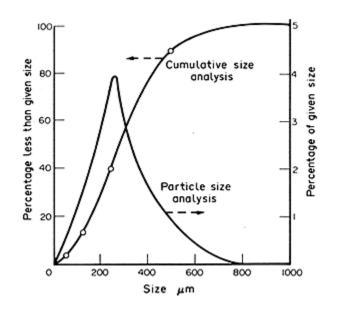
#### Increasing interest in nanomaterials

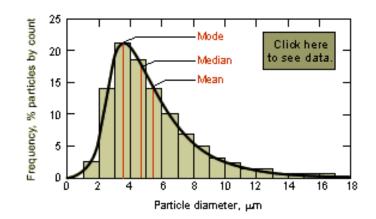
- ✓ Particle sizes < 100 nm are of interest</p>
- Most techniques in this range questionable
  - Dynamic Light Scattering
    - Provides Mean Size
    - Difficult if bimodal
- Agglomerates make sizing difficult

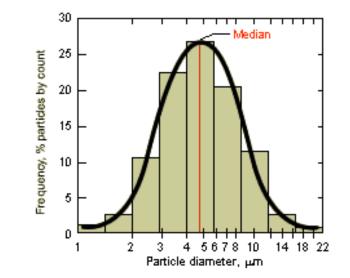
 Obtain average size of primary particles from the surface area and density of the material

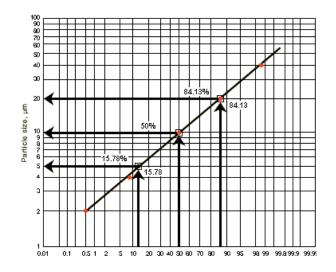




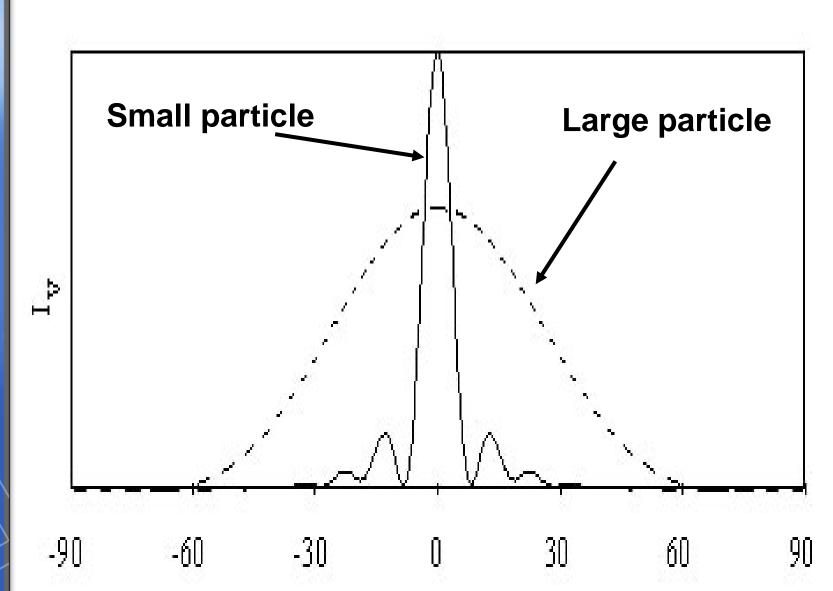


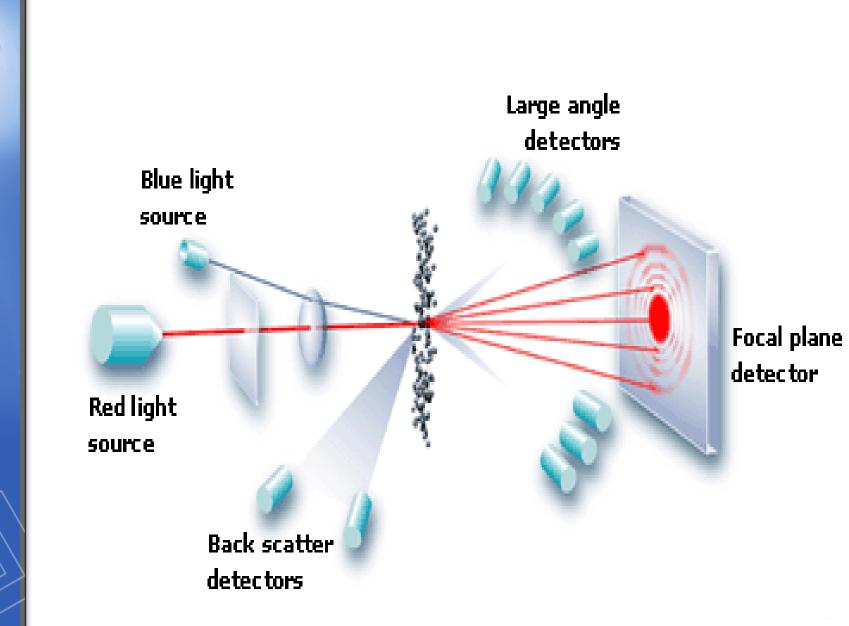




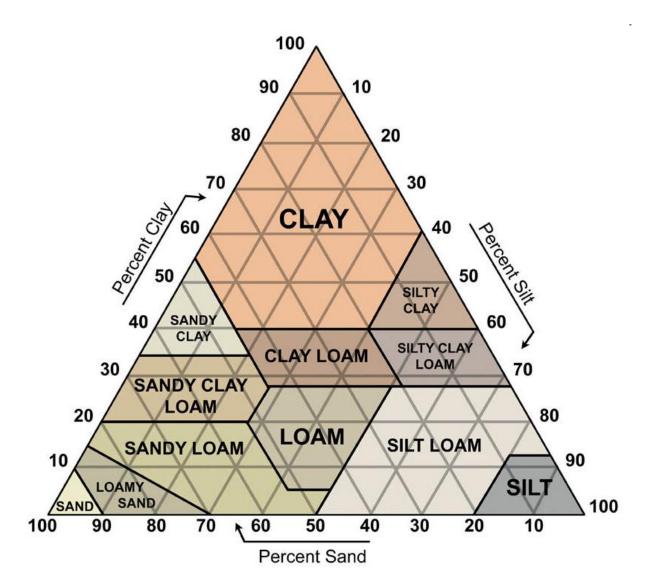


#### **Measuring : Laser diffraction**





# Quick and easy, but not really a distribution





Laser Light Scattering



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#### X-ray Sedimentation

#### Electrical Sensing Zone

